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APPLICATION NO.	FIL	ING DATE	FIRST NAMED INVENTOR,	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/613,148	07	7/07/2003	Koji Nagata	520.42915X00 6729	
20457	7590	10/18/2005		EXAMINER	
		Y, STOUT & KR EENTH STREET	JARRETT, RYAN A		
SUITE 1800 ARLINGTON, VA 22209-3873				ART UNIT	PAPER NUMBER
				2125	

DATE MAILED: 10/18/2005

Please find below and/or attached an Office communication concerning this application or proceeding.

		Application No.	Applicant(s)	
		10/613,148	NAGATA ET AL.	
	Office Action Summary	Examiner	Art Unit	
		Ryan A. Jarrett	2125	
 Period for l	The MAILING DATE of this communication app Reply	ears on the cover sheet with the c	orrespondence address	
A SHOF WHICH - Extensic after SIX - If NO pe - Failure t Any repl	RTENED STATUTORY PERIOD FOR REPLY EVER IS LONGER, FROM THE MAILING DA ons of time may be available under the provisions of 37 CFR 1.13 ((6) MONTHS from the mailing date of this communication. riod for reply is specified above, the maximum statutory period w o reply within the set or extended period for reply will, by statute, y received by the Office later than three months after the mailing patent term adjustment. See 37 CFR 1.704(b).	ATE OF THIS COMMUNICATION 36(a). In no event, however, may a reply be tirr will apply and will expire SIX (6) MONTHS from a cause the application to become ABANDONEI	lely filed the mailing date of this communication. (35 U.S.C. § 133).	
Status				
1)⊠ R 2a)⊠ Ti 3)⊟ S	esponsive to communication(s) filed on 28 Set his action is FINAL . 2b) This ince this application is in condition for allowards osed in accordance with the practice under E	action is non-final. nce except for formal matters, pro		
Dispositior	o of Claims			
4a 5)⊠ C 6)⊠ C 7)⊠ C	laim(s) <u>1-15</u> is/are pending in the application. Of the above claim(s) is/are withdraw laim(s) <u>1-10</u> is/are allowed. laim(s) <u>11-13</u> is/are rejected. laim(s) <u>14 and 15</u> is/are objected to. laim(s) are subject to restriction and/or appears.	vn from consideration.		
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10)□ Th Al R	the specification is objected to by the Examine the drawing(s) filed on is/are: a) acception and acception and request that any objection to the explacement drawing sheet(s) including the correct the oath or declaration is objected to by the Example 1.	epted or b) objected to by the Eddrawing(s) be held in abeyance. See ion is required if the drawing(s) is obj	e 37 CFR 1.85(a). ected to. See 37 CFR 1.121(d).	
Priority un	der 35 U.S.C. § 119			
a)⊠ 1. 2. 3.	cknowledgment is made of a claim for foreign All b) Some * c) None of: Certified copies of the priority documents Certified copies of the priority documents Copies of the certified copies of the priority documents application from the International Bureau the attached detailed Office action for a list	s have been received. s have been received in Application rity documents have been received u (PCT Rule 17.2(a)).	on No ed in this National Stage	
Attachment(s) of References Cited (PTO-892)	4) Interview Summary		
2) Notice o	of Draftsperson's Patent Drawing Review (PTO-948) tion Disclosure Statement(s) (PTO-1449 or PTO/SB/08) to(s)/Mail Date	Paper No(s)/Mail Da		

DETAILED ACTION

1. Applicant's arguments, see page 8, filed 9/28/05, with respect to the rejection under 35 USC 101 have been fully considered and are persuasive. The 35 USC 101 rejection of claim 11-15 has been withdrawn.

Applicant's amendment to claims 2, 3, and 5, filed 9/28/05, has overcome the rejection of these claims under 35 USC 112, 2nd paragraph.

Some of Applicant's arguments, see pages 9-12, filed 9/28/05, coupled with the amendment to claims 1 and 3 have been fully considered and are persuasive. The 35 USC 102 rejections of claims 1-10 have been withdrawn. The rejection is withdrawn since Examiner agrees that Cooke and Kamiyama fail to teach the feature added to these claims in the amendment filed 9/28/05.

Applicant did not make the corresponding amendment to independent claim 11. Therefore, claims 11-13 are rejected under 35 USC 102 for the same reason that previous claims 3-5 were rejected. Claims 11-13 are essentially identical to the previous version of claims 3-5, except for the fact that they are drawn to a method and not an apparatus. Claims 11-13 were rejected under 35 USC 101, and claims 11-13 were additionally intended to be rejected under 35 USC 102 for the same reasons as previous claims 3-5, but they were inadvertently omitted from this rejection paragraph. But more importantly, the rejection below is not considered to be a "new" rejection since the prior art was already applied in a separate rejection to nearly identical claims. Thus, the Applicant has had to opportunity to amend and/or argue the merits of the claim

versus the prior art, which he has done. So the finality of this action is considered proper.

The 35 USC 102 rejection of claims 11-15 is "maintained" for the at least the following reason: Applicant argues that Cooke provides no disclosure or suggestion for applying pattern vertex data to define the pattern shapes. Rather, Applicant agues, Cooke utilizes a system wherein an initial point is used in conjunction with the length of the pattern in the x and y directions. However, this teaching of Cooke is analogous to the claimed pattern vertex data, or the pair of opposite corner point coordinates. In Cooke, the four corner point coordinates are defined by (X,Y), (X, LX), (Y,LY), and (LX, LY).

Claim Rejections - 35 USC § 102

2. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.
- 3. Claims 11-13 are rejected under 35 U.S.C. 102(b) as being anticipated by Cooke US 4,482,810. For example Cooke discloses:
- 11. An exposure method, comprising the steps of: applying a charged particle beam or a light onto a sample while controlling the application using pattern shape data in a bitmap format, and exposing a desired pattern onto the sample; decomposing the pattern shape into plurality of rectangle patterns parallel to any one coordinate axis of the orthogonal coordinates defined on the sample, and converting the pattern shape into the data format for expressing the pattern shape by a pair of opposite corner point

coordinates of each line parallel to any one coordinate axis of the orthogonal coordinates defined on the sample; grouping corner point data representing the respective rectangle patterns on a per given coordinate area basis, and sorting the respective grouped corner point data by reference to the coordinates of the respective corner point data; and rejecting an overlap area between patterns from the respective sorted corner point data; wherein the pattern shape data in the bitmap format based on the result of the overlap rejection function (e.g., col. 3 line 25 - col. 4 line 2, col. 7 line 67 - col. 8 line 12, claims 1-6).

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- 12. The exposure method according to claim 11, wherein the coordinate area for grouping the respective corner point data is area corresponding to an array of pixels arranged adjacent to each other in a direction parallel to any one coordinate axis of the orthogonal coordinates defined on the sample out of pixel arrays of the bitmap (e.g., Figs. 6-8).
- 13. The exposure method according claim 11, wherein the line formed by the pair of the corner points representing the pattern and the direction of the bitmap pixel array for grouping the corner point data are parallel to each other, and the direction of the bitmap pixel array for grouping the corner point data and the direction of scanning of the charged beam or light are parallel to each other (e.g., Figs. 6-8).
- 4. Claims 1-5 and 10 are additionally rejected under 35 U.S.C. 102(b) as being anticipated by Kamiyama et al. US 6,271,852. For example, Kamiyama et al. discloses:
- 11. An exposure method, comprising the steps of: applying a charged particle beam or a light onto a sample while controlling the application using pattern shape data in a bitmap format, and exposing a desired pattern onto the sample; decomposing the pattern shape into plurality of rectangle patterns parallel to any one coordinate axis of the orthogonal coordinates defined on the sample, and converting the pattern shape into the data format for expressing the pattern shape by a pair of opposite corner point coordinates of each line parallel to any one coordinate axis of the orthogonal coordinates defined on the sample; grouping corner point data representing the respective rectangle patterns on a per given

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coordinate area basis, and sorting the respective grouped corner point data by reference to the

coordinates of the respective corner point data; and rejecting an overlap area between patterns from the

respective sorted corner point data; wherein the pattern shape data in the bitmap format based on the

result of the overlap rejection function (e.g., Fig. 30A, Fig. 30B, col. 3 line 35 - col. 5 line 17).

12. The exposure method according to claim 11, wherein the coordinate area for grouping

the respective corner point data is area corresponding to an array of pixels arranged adjacent to each

other in a direction parallel to any one coordinate axis of the orthogonal coordinates defined on the

sample out of pixel arrays of the bitmap (e.g., Fig. 30A, Fig. 30B, col. 3 line 35 - col. 5 line 17).

13. The exposure method according claim 11, wherein the line formed by the pair of the

corner points representing the pattern and the direction of the bitmap pixel array for grouping the corner

point data are parallel to each other, and the direction of the bitmap pixel array for grouping the corner

point data and the direction of scanning of the charged beam or light are parallel to each other (e.g., Fig.

30A, Fig. 30B, col. 3 line 35 – col. 5 line 17).

Allowable Subject Matter

5. Claims 1-10 are allowed.

6. Claims 14 and 15 are objected to as being dependent upon a rejected base

claim, but would be allowable if rewritten in independent form including all of the

limitations of the base claim and any intervening claims.

Conclusion

7. THIS ACTION IS MADE FINAL. Applicant is reminded of the extension of time

policy as set forth in 37 CFR 1.136(a).

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A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the mailing date of this final action.

8. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Ryan A. Jarrett whose telephone number is (571) 272-3742. The examiner can normally be reached on 10:00-6:30 M-F.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Leo Picard can be reached on (571) 272-3749. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

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Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Ryan A. Jarrett Examiner Art Unit 2125

10/11/05 RAJ

> LEO PICARD SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 2100

L-P.P.